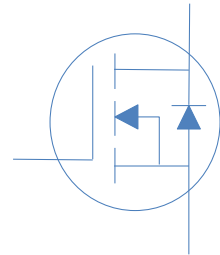




## 30V N-Ch Power MOSFET

$V_{DS}$		30	V
$R_{DS(on),max}$	$V_{GS}=10V$	2.9	m
$R_{DS(on),max}$	$V_{GS}=4.5V$	4	m
$I_D$		122	A



Part Number	Package	Marking
HTN027N03P	DFN5x6	TN027N03P

**Absolute Maximum Ratings at  $T_J=25$  (unless otherwise specified)**

Parameter	Symbol	Conditions	Value	Unit
Continuous Drain Current (Silicon Limited)	$I_D$	$T_C=25$	122	A
		$T_C=100$	77	
Drain to Source Voltage	$V_{DS}$	-	30	V
Gate to Source Voltage	$V_{GS}$	-	$\pm 20$	V
Pulsed Drain Current	$I_{DM}$	-	103	A
Avalanche Energy, Single Pulse	$E_{AS}$	$L=0.1mH, T_C=25$	101	mJ
Power Dissipation	$P_D$	$T_C=25$	78	W
Operating and Storage Temperature	$T_J, T_{stg}$	-	-55 to 150	

**Absolute Maximum Ratings**

Parameter	Symbol	Max	Unit
Thermal Resistance Junction-Case	$R_{JC}$	1.6	/W
Thermal Resistance Junction-Ambient	$R_{JA}$	55	/W

**Electrical Characteristics at  $T_J=25$  (unless otherwise specified)**
**Static Characteristics**

Parameter	Symbol	Conditions	Value			Unit
			min	typ	max	
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250 A$	30	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250 A$	1	-	2	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{GS}=0V, V_{DS}=24V, T_J=25$	-	-	1	A
Gate to Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	$\pm 100$	nA
Drain to Source on Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$	-	-	2.9	m
		$V_{GS}=4.5V, I_D=15A$	-	-	4.0	m
Transconductance	$g_{fs}$	$V_{DS}=10V, I_D=5A$	-	15	-	S
Gate Resistance	$R_G$	$V_{GS}=0V, V_{DS}$ Open, $f=1MHz$	-	2.6	-	

**Dynamic Characteristics**

Input Capacitance	$C_{iss}$	$V_{GS}=0V, V_{DS}=15V, f=1MHz$	-	4242	-	pF
Output Capacitance	$C_{oss}$		-	492	-	
Reverse Transfer Capacitance	$C_{rss}$		-	329	-	
Total Gate Charge (10V)	$Q_g (10V)$	$V_{DD}=25V, I_D=14A, V_{GS}=10V$	-	88	-	nC
Gate to Source Charge	$Q_{gs}$		-	7	-	
Gate to Drain (Miller) Charge	$Q_{gd}$		-	24	-	
Turn on Delay Time	$t_{d(on)}$	$V_{DD}=15V, I_D=1A, V_{GS}=10V, R_G=2.5 \Omega$	-	33	-	ns
Rise time	$t_r$		-	23	-	
Turn off Delay Time	$t_{d(off)}$		-	72	-	
Fall Time	$t_f$		-	25	-	

**Reverse Diode Characteristics**

Diode Forward Voltage	$V_{SD}$	$V_{GS}=0V, I_F=15A$	-	0.79	1.1	V
Reverse Recovery Time	$t_{rr}$	$I_F=15A, di_F/dt=100A/\mu s$	-	19.8	-	ns
Reverse Recovery Charge	$Q_{rr}$		-	8.7	-	nC



Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

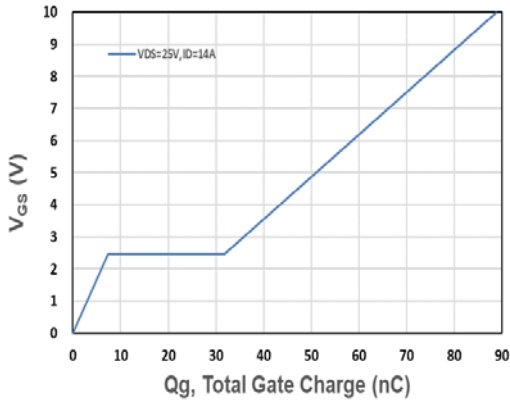


Figure 8. Typical Capacitance vs. Drain-to-Source Voltage

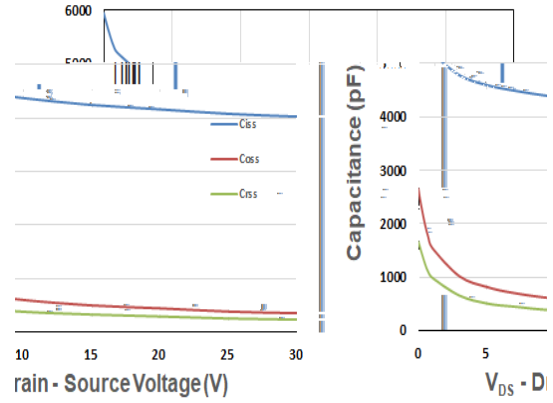


Figure 9. Maximum Safe Operating Area

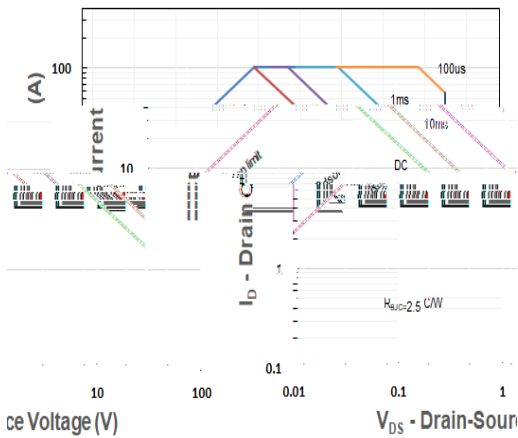


Figure 10. Maximum Drain Current vs. Case Temperature

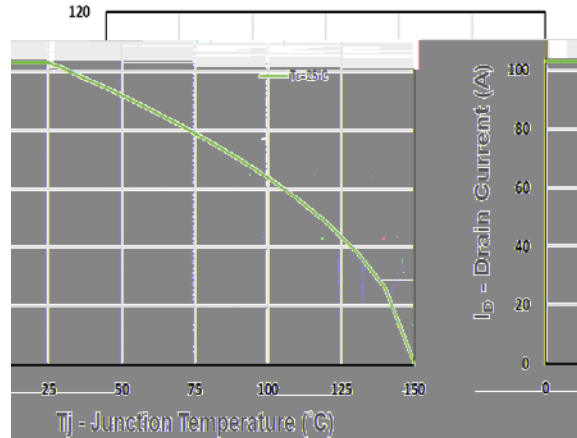
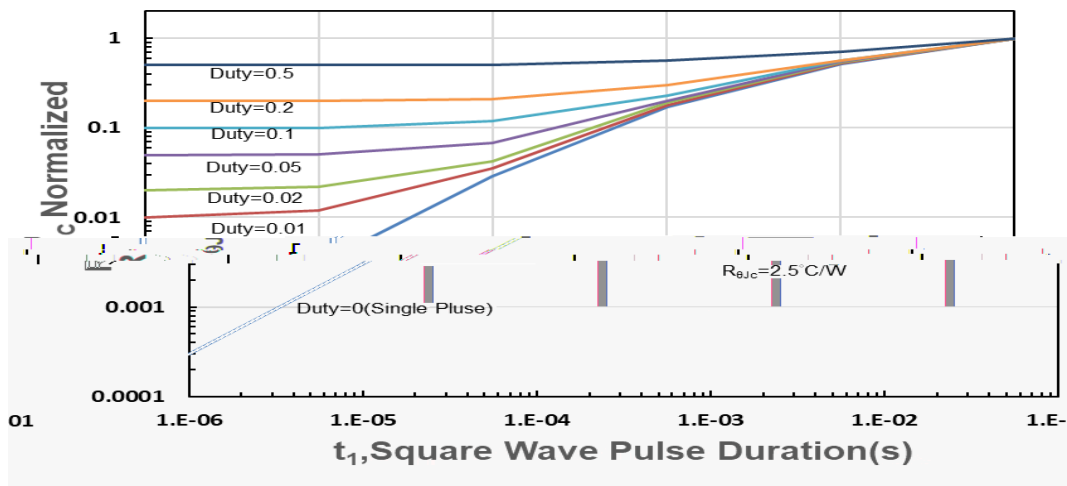


Figure 11. Normalized Maximum Transient Thermal Impedance, Junction-to-Case



Inductive switching Test	

Gate Charge Test	

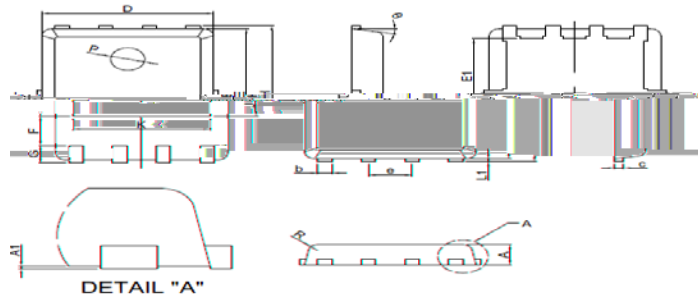
Uclamped Inductive Switching (UIS) Test	

Diode Recovery Test	

Package Outline

DFN5x6\_P, 8 Leads



SYMBOL	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	0.80	1.00		
A1	0.00	0.05		
b	0.35	0.49		
c	0.254 REF			
D	4.90	5.10	0.193	0.201
F	1.4 REF			
E	5.70	5.90	0.224	0.232
e	1.27 BSC			
H	5.95	6.20	0.234	0.244
L1	0.10	0.18		
G	0.6 REF			
K	4 REF			
L		0.15		
J	0.95 BSC			
P	1 REF			
E1	3.4 REF			
Ø	6°	14°		
R	0.25 REF			